

# Architecture for a High Speed SAR ADC

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## Problem Definition

Derive a topology that will minimize power while achieving 12 bits of resolution and 200MSPS speed . Make topology amenable for future interleaving that can improve speed.

## Problem Analysis

We are given an input  $x \in [-1, 1]$  and converter tries to find  $K$  such that

$$-1 + K\Delta \leq x \leq -1 + (K + 1)\Delta.$$

If input is uniformly distributed then the problem will require a minimum  $N = \log_2(2/\Delta)$  “Yes or No” questions with precise answers. From a circuit perspective “Yes or No” is that of a comparator comparing input with a threshold with infinite precision. If the comparison has finite precision i.e it is unreliable for  $|inp| < \epsilon$  then at the end of  $N$  questions input can be as far as  $\epsilon$  away from the said range.

A typical SAR ADC conversion proceeds as follows . We compare the input with a threshold  $V_{th}(k) = r(k) * (x_{max}(k) + x_{min}(k)) + \epsilon(k)$  where it's guaranteed by previous knowledge that  $x \in [x_{max}(k), x_{min}(k)]$ . At the end of comparison the input is guaranteed to be in  $[x_{max}(k), V_{th}(k)]$  or  $[x_{min}(k), V_{th}(k)]$  so by setting  $x_{max}(k+1)$  and  $x_{min}(k+1)$  accordingly we can guarantee that range in which input can lie  $S(k+1) = x_{max}(k+1) - x_{min}(k+1) < S(k)$  provided that we put the thresholds  $V_{th}(k) \in [x_{max}(k), x_{min}(k)]$  . This by iteration can guarantee that we can locate input to a finite precision in required number of steps.

## Sampling Circuit

Noise power due to Differential sampling referred to input

$$P_{noise} = 2 * \frac{KT}{C_s} * \frac{Cs + Cp}{Cs}$$

where  $Cs$  = sampling cap and  $Cp$  = parasitic cap on top-plate , assuming top plate switch is limiting bandwidth and contributing most of noise compared to bottom plate switch . This is a reasonable assumption as every attempt will be made to minimize the top plate switch to reduce charge injection offset. Input referred SNR assuming differential swing of  $\pm V_{REF}$

$$SNR = V_{REF}^2 / 2 * P_{noise}$$

Assuming a shrink of .8 and  $V_{REF} = 0.9$ , for a noise performance equaling 12 bit quantization noise

$$P_{noise} = \Delta^2 / 12$$

$$Cs = 600fF$$

## 0.1 Clocked Comparator

In a latched comparator  $V_{in} * e^{t/\tau} = VDD$ . For a minimum resolution input  $V_\delta$  it will need a time  $T_\delta = \tau * \ln(VDD/V_\delta)$ . Input greater than  $V_\delta$  needs time less than  $T_\delta$ . An asynchronous ADC uses this fact for optimization by making every comparison time just enough to make accurate decision by checking output differential level against VDD or timing out after  $T_{max}$ . Hence

$$T_{cmp} = \tau * \ln(VDD/V_{in}).$$

This makes the conversion time input dependant and the worst case comparison time =  $N^2/2 * \tau * \ln(2)$  is a two fold improvement in comparison time. But power saving may be significantly higher if actives are powered down after conversion and negligible if all power is dynamic. For a latch  $\tau = Gm/C = \beta * \sqrt{w}/C_{oxl} * W + C_{load}$ . if offset is non critical (SAR) or calibrated (multibit) no optimization is possible in this end. At higher precision ( $V_\delta = 10mV = 8bit$ ) noise (thermal/capacitive coupling noise  $\propto \frac{1}{C}$ ) from this may become critical and a switch from a noisy to low noise latch may be required. This will increase W and hence  $\tau$ .

A Way to improve the comparison time from  $O(N^2)$  to  $O(N)$  will be to add gain stages in front of the Clocked comparator to the tune of  $2^k$  for  $k^{th}$  comparison. This will make comparison time constant for all clocks making comparison time  $N * \tau * \ln(2)$ . But this will add to settling portion of conversion time and will be a trade off. This will automatically improve noise performance w.r.t clocked comparator.

Another option is to add a pipelined clocked comparator to the first one but not wait for it. So output of second latch will be  $V_{in} * e^{(t1+t2)/\tau}$  making its resolution better

## Non binary SAR

In a SAR ADC without any redundancy  $k_{th}$  DAC step  $S(k)$  needs to settle to  $1LSB = VREF/2^N$  for ADC to converge correctly. In a constant clock environment this requires a time  $T_{dac} = \tau * N * \ln(2)$  corresponding to worst case first step and hence a total DAC time of  $\tau * N^2 * \ln(2)$ . If each DAC step gets a settling time just enough to meet the settling requirement then  $T_{dac}(k) = \tau * (N - k) * \ln(2)$  and total dac time will be  $\tau * N(N - 1)/2 * \ln(2)$ . To make  $T_{DAC}$  a constant we need redundancy propotional to current step so that an error  $S(k) * e^{-T_{dac}/\tau}$  can be tolerated. For this

$$\begin{aligned} \sum_{(k+1)}^N S(i) &= (1 + m) * S(k) \\ \sum_{(k+2)}^N S(i) &= (1 + m) * S(k + 1) \\ S(k + 1) &= (1 + m) * (S(k) - S(k + 1)) \\ S(k + 1) &= (1 + m)/(2 + m) * S(k) \end{aligned}$$

This Points to a non binary radix  $r = (1 + m)/(2 + m)$ . since redundancy greater than a step is not required  $m < 1$  and  $r < 2/3$ . Total conversion clock =  $\tau * \ln(1/m) * \ln(2) * \ln(m + 1)/\ln(2 + m)$ . Though this points to a near zero conversion time with  $m=1$  its a mathematical anomaly because of approximating error as  $S(k) * e^{-T_{dac}/\tau}$ . More correct Derivation is as follows (assumes non binary sar)

$$\begin{aligned} settlerror &= \sum_1^k S(i) * e^{(-(k-i)*T_{clk}+T_{dac})/\tau} \\ S(k) &= 1/2 * r^{(k-1)} \\ settlerror &= 1/2 * r^{(k-1)} * e^{-T_{dac}/\tau} * \sum_0^{k-1} r^{-i} * e^{-iT_{clk}/\tau} \\ settlerror &= 1/2 * r^{(k-1)} * e^{-T_{dac}/\tau} * (1 - r^{-k} * e^{-k*T_{clk}/\tau}) / (1 - r^{-1} * e^{-T_{clk}/\tau}) \\ e^{-T_{clk}/\tau} &< r \\ settlerror &= 1/2 * r^{(k-1)} * e^{(-T_{clk}/\tau)} / (1 - r^{-1} * e^{-T_{clk}/\tau}) = m * 1/2 * r^{(k-1)} \\ e^{-T_{dac}/\tau} &= m/(1 + rm) < r \\ r &= 1/2 \\ T_{dac} &= 2 * \ln(2) * \tau; \end{aligned}$$

In a constant clock binary asynchronous ADC 's advantageous to constraint

$$T_{cmp}(k) + T_{dacNamp}(k + 1) = T_{clk}$$

This is because if  $(k + 1)^{th}$  decision is critical  $k^{th}$  decision is non critical and should take less time which can be used to make  $(k + 1)^{th}$  decision more precise. Also  $(k + 1)^{th}$  decision will take more time but since  $(k + 2)^{th}$  decision is noncritical its dac settling error doesnt matter.